

The Potentialities of H⁻ beam Diagnostics by Detached Particles, A. ARTIOMOV, JINR - A comparative analysis of proposed methods of H⁻ beam diagnostics by secondary particles, which are produced from the detachment of a part of the ions in thin probing particle or photon targets, is presented. The estimate of the measurement accuracies for various beam parameters and used targets is made. As shown, using a photon target, wider potentialities of nonperturbative beam diagnostics can be achieved from the viewpoint of accuracies and the spectrum of compact diagnostic apparatus.